INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)

Docket Number (Optional) TWI-11720	Application Number NEW		
Applicant(s) Louis N. Koppel et al.			
Filing Date HEREWITH	Group Art Unit Unknown		

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	Name	CLASS	SUBCLASS	FILING DATE
#X	*AA	5,042,951	08/27/1991	Gold et al.	356	369	09/19/1989
3K	*AB	5,412,473	05/02/1995	Rosencwaig et al.	356	351	07/16/1993
¥K	*AC	5,475,728	12/12/1995	Smith et al.	378	81 .	08/02/1993
≯ K	*AD	5,619,548	04/08/1997	Koppel	378	70	08/11/1995
XX	*AE	5,878,106	03/02/1999	Fujiwara	378	79	05/29-96
ZK	*AF	5,923,720	07/13/1999	Barton et al.	378	84	06/17/1997
±K	*AG	6,041,098	03/21/2000	Touryanski et al.	378	70	02/02/1998
IK	*AH	6,069,934	05/30/2000	Verman et al.	378	73	04/07/1998
30K							

FOREIGN PATENT DOCUMENTS

		DOCUMENT					TRANSLATION	
	REF	Number	DATE	COUNTRY	CLASS	SUBCLASS	YES	No
XX	*AI	144 956	11/12/1980	Germany	G01B	15/02		X
*K	*AJ	WO 92/08104	05/14/1992	PCT	G01B	11/24		
#1	*AK	20011116705	04/27/2001	Japan	G01N	23/207	Abstract	
*K								

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

#K	*AL	K. Sakurai et al., "Fourier Analysis of Interference Structure in X-Ray Specular Reflection from Thin Films," Jpn. J. Appl. Phys., Vol. 31, 1992, pp. L113-L115.
#K	*AM	K.N. Stoev et al., "Review on grazing incidence X-ray spectrometry and reflectometry," Spectrochimica Acta Part B, Vol. 54, 1999, pp. 41-82.
3 K	*AN	N. Wainfan et al., "Density Measurements of Some Thin Copper Films," Journal of Applied Physics, Vol. 30, No. 10, October 1959, pp. 1604-1609.
33 1	*AO	J.P. Sauro et al., "Some Observations on the Interference Fringes Formed by X Rays Scattered from Thin Films," <i>Physical Review</i> , Vol. 143, No. 1, March 1966, pp. 439-443.
XK	*AP	K. Sakurai et al., "Analysis of thin films by X-ray scattering at grazing incidence," SPring-8 User Experiment Report No. 2 (1998 A), March 1999, p. 162.
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Examiner	I. Kihrada	Date Considered	03/03/2004				
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if							
not in conformance and not considered. Include copy of this form with next communication to applicant.							